

# N-Channel Enhancement Mode Power MOSFET

#### Description

The HM4488 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

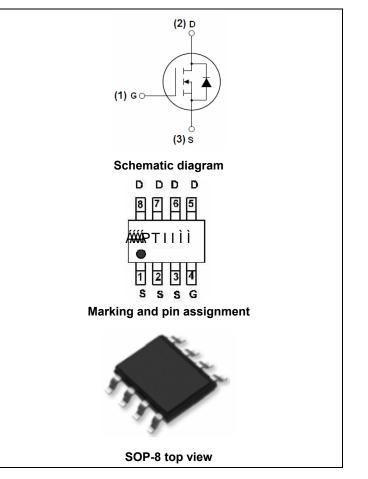
#### **General Features**

- $V_{DS} = 150V, I_D = 5.2A$  $R_{DS(ON)} < 44m\Omega @ V_{GS} = 10V$  (Typ:  $31m\Omega$ )
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Low gate to drain charge to reduce switching losses

#### Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

#### 100% ΔVds TESTED!



### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
PTIIÌÌ	PTIIÌÌ	SOP-8	Ø330mm	12mm	2500 units

### Absolute Maximum Ratings (T<sub>A</sub>=25℃unless otherwise noted)

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Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	150	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	I <sub>D</sub>	5.2	А
Drain Current-Continuous(T <sub>C</sub> =100℃)	I <sub>D</sub> (100℃)	3.7	А
Pulsed Drain Current(Note 1)	I <sub>DM</sub>	42	А
Maximum Power Dissipation	PD	3.5	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 150	°C

### **Thermal Characteristic**

Thermal Resistance, Junction-to-Case(Note 2)	R <sub>eJC</sub>	35.7	°C <b>/W</b>	
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### Electrical Characteristics (T<sub>A</sub>=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	150	170	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =150V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250µA	2.5	3.2	4.5	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =5.2A	-	31	44	mΩ
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =50V,I <sub>D</sub> =5.2A	12	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C <sub>lss</sub>		-	1700	-	PF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V, F=1.0MHz	-	190	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	90	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t <sub>d(on)</sub>		-	15	-	nS
Turn-on Rise Time	tr	V <sub>DD</sub> =75V,I <sub>D</sub> =3.1A	-	13	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{GEN}$ =6.5 $\Omega$	-	26	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	14	-	nS
Total Gate Charge	Qg	V <sub>DS</sub> =75V,I <sub>D</sub> =3.1A,	-	35.8	-	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =75V,I <sub>D</sub> =5.1A, V <sub>GS</sub> =10V	-	7.5	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	VGS-10V	-	13	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =3.1A	-	-	1.2	V
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	2.7	А
Reverse Recovery Time	trr	$T_J$ = 25°C, $I_F$ = 3.1A,	-	50	-	nS
Reverse Recovery Charge	Qrr	V <sub>DD</sub> = 25V,di/dt = 100A/µs	-	140	-	nC

Notes:

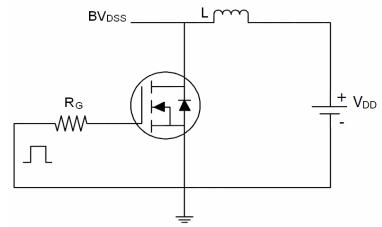
1. Repetitive Rating: Pulse width limited by maximum junction temperature.

- **3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.
- 4. Guaranteed by design, not subject to production.

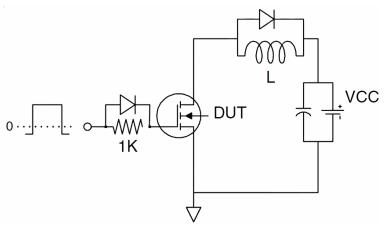
**<sup>2.</sup>** Surface Mounted on FR4 Board,  $t \le 10$  sec.



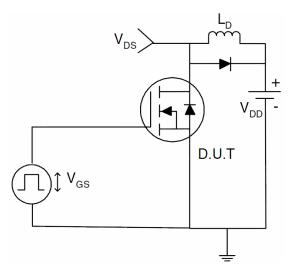
### Test Circuit 1) E<sub>AS</sub> test Circuits



#### 2) Gate charge test Circuit

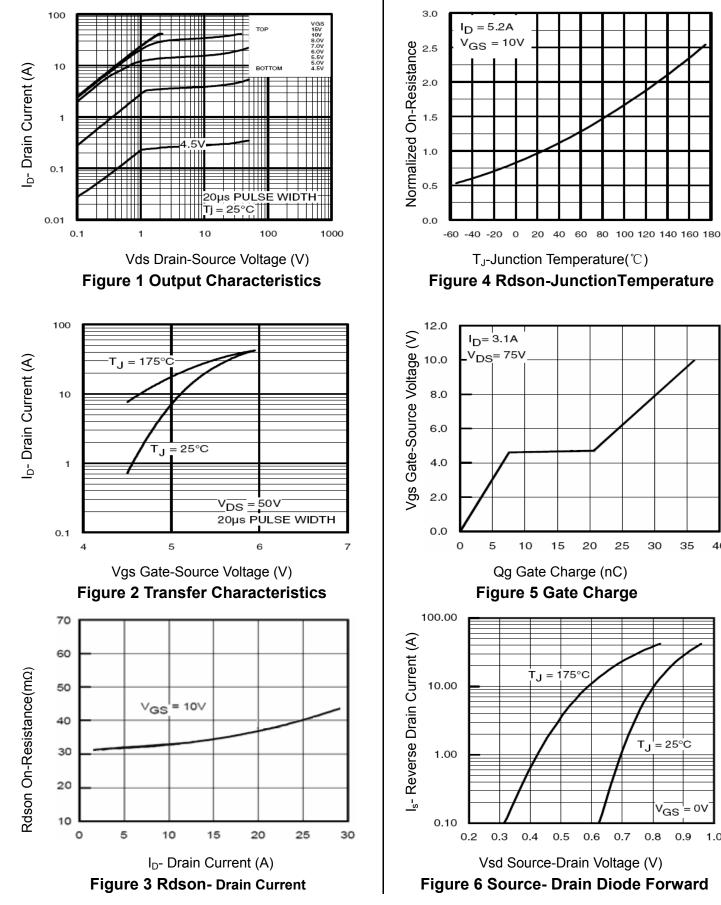


#### 3) Switch Time Test Circuit





## **Typical Electrical and Thermal Characteristics (Curves)**

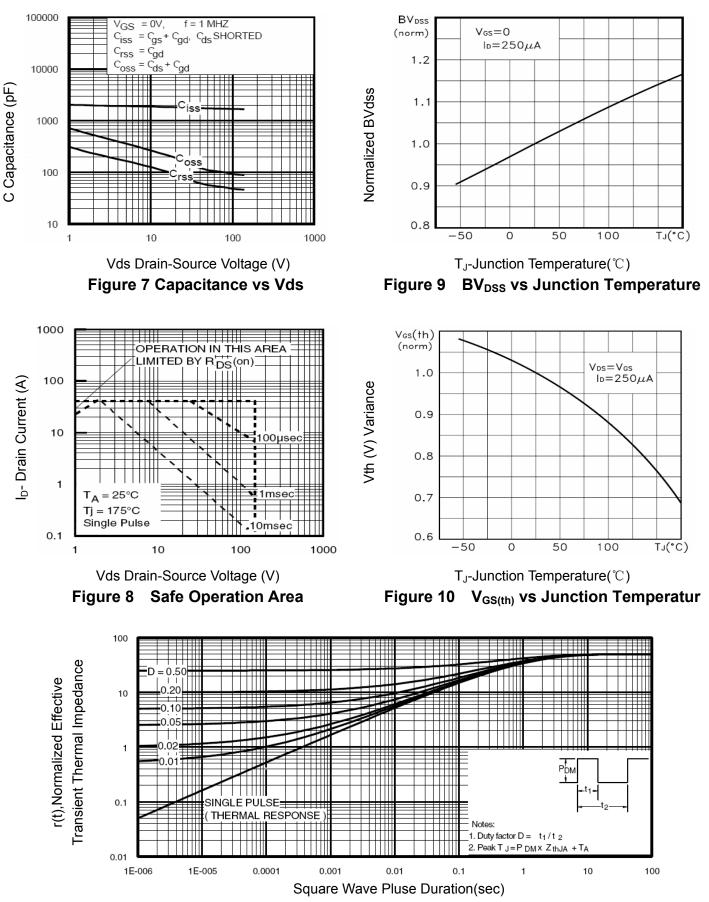


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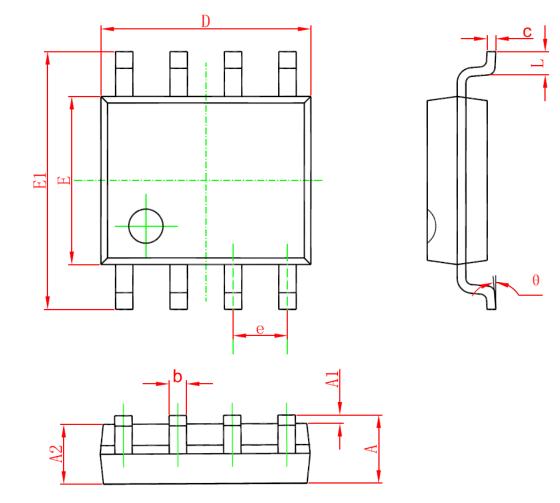








# **SOP-8 Package Information**



Cumbral	Dimensions Ir	n Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0. 010	
A2	1. 350	1. 550	0. 053	0. 061	
b	0. 330	0.510	0.013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
E	3.800	4.000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0.016	0. 050	
θ	0°	8°	0°	8°	





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